Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/759,414	LI, ZHE	
Examiner	Art Unit	
Thomas H. Stevens	2123	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES				
(INCLUDING SEARCH	DATE	EXMR		
Google: Inventor Scholar	113/06	27		
Google Scholar: Aightal functional circuit; INSPEC: Inventor IREE INSPEC:				
"de bugger "Probe"				
"circuit"	J/	1		